

## 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20180927003.2A PO Thickness change on the LBC7 process node Change Notification / Sample Request

**Date:** January 04, 2019 **To:** PREMIER FARNELL PCN

Dear Customer:

# PCN Revision A is to announce the retraction of select devices.

This is an announcement of change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. If samples or additional data are required, requests must be received within 30 days of acknowledgement as samples are not built ahead of the change. You may contact the PCN Manager or your local Field Sales Representative to acknowledge this PCN and request samples or additional data.

The changes discussed within this PCN will not take effect until TI receives written customer approval. In order to assure continuity of supply, customer approval is requested no later than 1 month prior to the proposed 1st ship date indicated on the following pages.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN ww\_admin\_team@list.ti.com).

Sincerely,

PCN Team SC Business Services

# 20180927003.2A Attachment: 1

# **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

**DEVICE**TPS621700DSGTQ1

**CUSTOMER PART NUMBER** 

null

Technical details of this Product Change follow on the next page(s).

PCN Number: 201			180927003.2 <mark>A PCN</mark>			CN [	<b>Date:</b> Jan. 4, 2019		Jan. 4, 2019	
Title:	Title: LBC7 change total PO thickness from 24kA to 39kA									
<b>Customer Contact:</b>			<u>PCN</u>	l <u>Manager</u>		D	ept:			Quality Services
Proposed 1 <sup>st</sup> Ship Date:			Anr	. 15, 2019		Estimate		ımp	le	Date provided at
		•	Αρι. 13, 2013			Availability:			sample request.	
Change T			$\overline{\Box}$	Assessable Due				$\overline{\Box}$	Λ -	
Desig	nbly Site		Assembly Process Electrical Specification					Assembly Materials Mechanical Specification		
Test 9			Ħ	Packing/Shipping/Labeling			Ħ		Test Process	
	r Bump Site			Wafer Bump Material			Wafer Bump Process			
Wafe	r Fab Site			Wafer Fab Materials						
			Part number change							
				PCN I	<u> Deta</u>	nils				
	on of Change		A :-	L			. C		ا اد	and Datus stand day income
										ces. Retracted devices uct Affected Section.
			_	fected by this I	_	d in yenow	V III C	iie i	Tout	act Affected Section.
			<u> </u>		<b>O</b>					
				ince a total PO						
					to 18	3kA on the	LBC	7 pr	oces	ss node for the selected
devices iis	ted in the "Pro	auct A	пес	ted section.						
	Chan	ge Fro	rom			Change To				
13kA							kide + 18kA Teos Oxide + 8kA			
Nitride passiv							ide passivation			
										_
	Qual details are provided in the Qual Data Section.									
	or Change:									
Continuity	of supply.									
Anticipat	ed impact on	Form	, Fit	, Function, Qເ	uality	y or Relia	bility	y (p	osit	ive / negative):
None										
Changes	to product id	entific	atio	on resulting fr	rom	this PCN:				
None										
Product A	Affected:	T							,	
LM746100	DGKRQ1	LP591	.2Q1	.8DRVRQ1	PLPS	912Q1.25D	RVT	Q1	TP	S62160QDSGRQ1
LM746100	DGKTQ1	LP591	.2Q1	.8DRVTQ1	PLP5	912Q1.2DF	RVTQ	1	TP	S62160QDSGTQ1
LM746700	DGKRQ1	LP591	2Q2	.5DRVRQ1	PLPS	5912Q1.5DF	RVTQ	1	TP	PS62162QDSGRQ1
LM746700	DGKTQ1	LP591	.2Q2	.5DRVTQ1	PLP5	912Q1.8DF	RVTQ	1	TP	S62162QDSGTQ1
LP5912Q0	.9DRVRQ1	LP591	.2Q2	.8DRVRQ1	PLP5	912Q2.7DF	RVTQ	1	ŦŦ	2562170QDSGRQ1
	.9DRVTQ1			.8DRVTQ1		5912Q2.8DF				PS62170QDSGTQ1
	.1DRVRQ1			.0DRVRQ1		912Q3.0DF				PS62171QDSGRQ1
	.1DRVTQ1			.0DRVTQ1		5912Q3.3DF				PS62171QDSGTQ1
	.2DRVRQ1			.3DRVRQ1		5912Q5.5DF 5912Q5.5DF				PS62172QDSGRQ1
	.2DRVKQ1			.3DRVRQ1		_7407LQPW		_		PS62172QDSGTQ1
	.5DRVRQ1			OGKTQ1	IPL	407LQPWR	ŲI		11	S7A8801QRTJRQ1
LP5912Q1	.5DRVTQ1	PLP59	<u>, 1</u> 2Q	1.1DRVTQ1						

## Qualification Report

Miho: LBC7 - Thick TEOS at PO 2nd OX DEP

#### Approve Date 6-September-2018

#### **Product Attributes**

Attributes	Qual Device: TP\$563201DDCR
Assembly Site	JCET
Package Family	SOT-23-T
Wafer Fab Supplier	Miho
Wafer Process	LBC7
Flammability Rating	UL 94 V-0

<sup>-</sup> Qual Devices qualified at LEVEL 1-NACG: Devices TPS563201DDCR

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TP\$563201DDCR	
HAST	Biased HAST, 130C/85%RH	192 Hours	3/231/0	
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/Pass	
TC	Temperature Cycle, -65/150C	750 Cycles	3/231/0	

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

#### Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

## **Qualification Report**

FFAB: LBC7 - Thick TEOS at PO 2nd OX DEP

## Approve Date 10-September-2018

## **Product Attributes**

Attributes	Qual Device: TP\$62175DQCR	Qual Device: TPS62177DQCR
Assembly Site	CLARK	CLARK
Package Family	WSON	WSON
Wafer Fab Supplier	FFAB	FFAB
Wafer Process	LBC7	LBC7
Flammability Rating	UL 94 V-0	UL 94 V-0

<sup>-</sup> Qual Devices qualified at LEVEL 2-NACG: Devices TPS62175DQCR and TPS62175DQCR

## Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TP\$62175DQCR	Qual Device: TP\$62177DQCR
HAST	Biased HAST, 130C/85%RH	192 Hours	3/231/0	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/Pass	3/Pass
TC	Temperature Cycle, -65/150C	750 Cycles	3/231/0	3/231/0

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
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Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

## Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com